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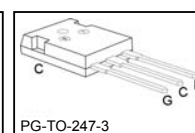
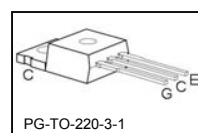
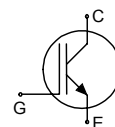
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# SGP30N60 SGW30N60

## Fast IGBT in NPT-technology

- 75% lower  $E_{off}$  compared to previous generation combined with low conduction losses
- Short circuit withstand time – 10  $\mu$ s
- Designed for:
  - Motor controls
  - Inverter
- NPT-Technology for 600V applications offers:
  - very tight parameter distribution
  - high ruggedness, temperature stable behaviour
  - parallel switching capability



- Qualified according to JEDEC<sup>1</sup> for target applications
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models : <http://www.infineon.com/igbt/>

Type	$V_{CE}$	$I_C$	$V_{CE(sat)}$	$T_j$	Marking	Package
SGP30N60	600V	30A	2.5V	150°C	G30N60	PG-TO-220-3-1
SGW30N60	600V	30A	2.5V	150°C	G30N60	PG-TO-247-3

### Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CE}$	600	V
DC collector current	$I_C$	41	A
$T_C = 25^\circ\text{C}$		30	
$T_C = 100^\circ\text{C}$			
Pulsed collector current, $t_p$ limited by $T_{jmax}$	$I_{Cpuls}$	112	
Turn off safe operating area	-	112	
$V_{CE} \leq 600\text{V}, T_j \leq 150^\circ\text{C}$			
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Avalanche energy, single pulse	$E_{AS}$	165	mJ
$I_C = 30\text{ A}, V_{CC} = 50\text{ V}, R_{GE} = 25\ \Omega,$ start at $T_j = 25^\circ\text{C}$			
Short circuit withstand time <sup>2</sup>	$t_{SC}$	10	$\mu$ s
$V_{GE} = 15\text{V}, V_{CC} \leq 600\text{V}, T_j \leq 150^\circ\text{C}$			
Power dissipation	$P_{tot}$	250	W
$T_C = 25^\circ\text{C}$			
Operating junction and storage temperature	$T_j, T_{stg}$	-55...+150	$^\circ\text{C}$
Soldering temperature, wavesoldering, 1.6mm (0.063 in.) from case for 10s	$T_s$	260	

<sup>1</sup> J-STD-020 and JESD-022

<sup>2</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.



# SGP30N60 SGW30N60

## Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
<b>Characteristic</b>				
IGBT thermal resistance, junction – case	$R_{thJC}$		0.5	K/W
Thermal resistance, junction – ambient	$R_{thJA}$	PG-TO-220-3-1	62	
		PG-TO-247-3-21	40	

## Electrical Characteristic, at $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	max.	
<b>Static Characteristic</b>						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=500\mu A$	600	-	-	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE} = 15V, I_C=30A$ $T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	1.7	2.1	2.4	
			-	2.5	3.0	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=700\mu A, V_{CE}=V_{GE}$	3	4	5	
Zero gate voltage collector current	$I_{CES}$	$V_{CE}=600V, V_{GE}=0V$ $T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	-	-	40	$\mu A$
			-	-	3000	
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0V, V_{GE}=20V$	-	-	100	nA
Transconductance	$g_{fs}$	$V_{CE}=20V, I_C=30A$	-	20	-	S
<b>Dynamic Characteristic</b>						
Input capacitance	$C_{iss}$	$V_{CE}=25V,$ $V_{GE}=0V,$ $f=1\text{MHz}$	-	1600	1920	pF
Output capacitance	$C_{oss}$		-	150	180	
Reverse transfer capacitance	$C_{rss}$		-	92	110	
Gate charge	$Q_{Gate}$	$V_{CC}=480V, I_C=30A$ $V_{GE}=15V$	-	140	182	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	$L_E$	PG-TO-220-3-1	-	7	-	nH
		PG-TO-247-3-21	-	13	-	
Short circuit collector current <sup>2)</sup>	$I_{C(SC)}$	$V_{GE}=15V, t_{SC}\leq 10\mu s$ $V_{CC}\leq 600V,$ $T_j\leq 150^\circ\text{C}$	-	300	-	A

<sup>2)</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.



# SGP30N60 SGW30N60

## Switching Characteristic, Inductive Load, at $T_j=25^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(on)}$	$T_j=25^\circ\text{C}$ , $V_{CC}=400\text{V}$ , $I_C=30\text{A}$ , $V_{GE}=0/15\text{V}$ , $R_G=11\Omega$ , $L_{\sigma}^{1)}$ = 180nH, $C_{\sigma}^{1)}$ = 900pF Energy losses include "tail" and diode reverse recovery.	-	44	53	ns
Rise time	$t_r$		-	34	40	
Turn-off delay time	$t_{d(off)}$		-	291	349	
Fall time	$t_f$		-	58	70	
Turn-on energy	$E_{on}$		-	0.64	0.77	mJ
Turn-off energy	$E_{off}$		-	0.65	0.85	
Total switching energy	$E_{ts}$		-	1.29	1.62	

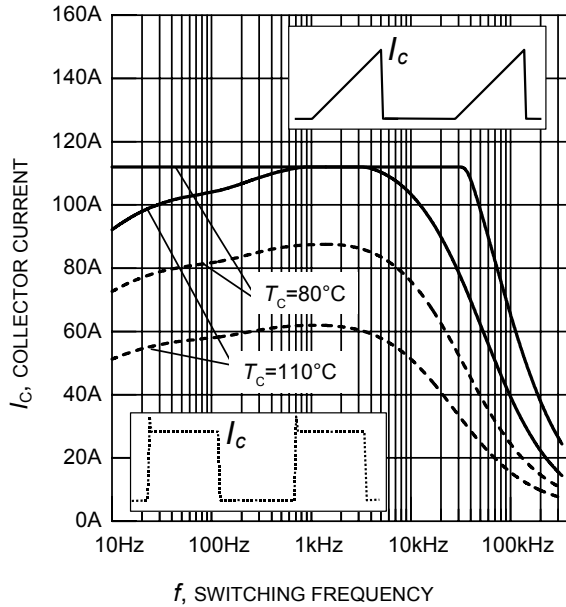
## Switching Characteristic, Inductive Load, at $T_j=150^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(on)}$	$T_j=150^\circ\text{C}$ $V_{CC}=400\text{V}$ , $I_C=30\text{A}$ , $V_{GE}=0/15\text{V}$ , $R_G=11\Omega$ , $L_{\sigma}^{1)}$ = 180nH, $C_{\sigma}^{1)}$ = 900pF Energy losses include "tail" and diode reverse recovery.	-	44	53	ns
Rise time	$t_r$		-	34	40	
Turn-off delay time	$t_{d(off)}$		-	324	389	
Fall time	$t_f$		-	67	80	
Turn-on energy	$E_{on}$		-	0.98	1.18	mJ
Turn-off energy	$E_{off}$		-	0.92	1.19	
Total switching energy	$E_{ts}$		-	1.90	2.38	

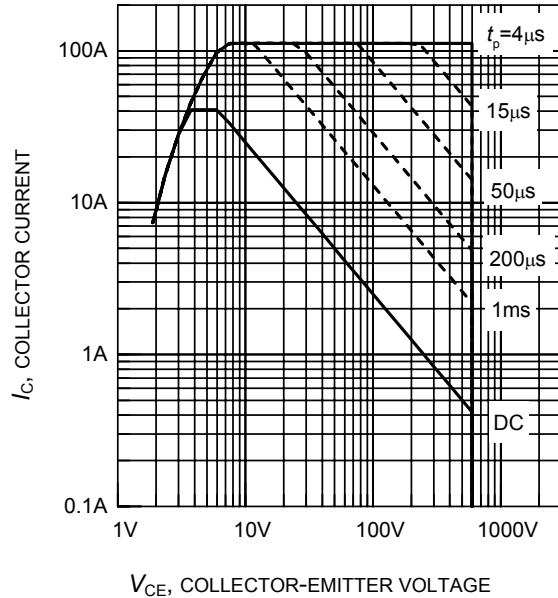
<sup>1)</sup> Leakage inductance  $L_{\sigma}$  and Stray capacity  $C_{\sigma}$  due to dynamic test circuit in Figure E.



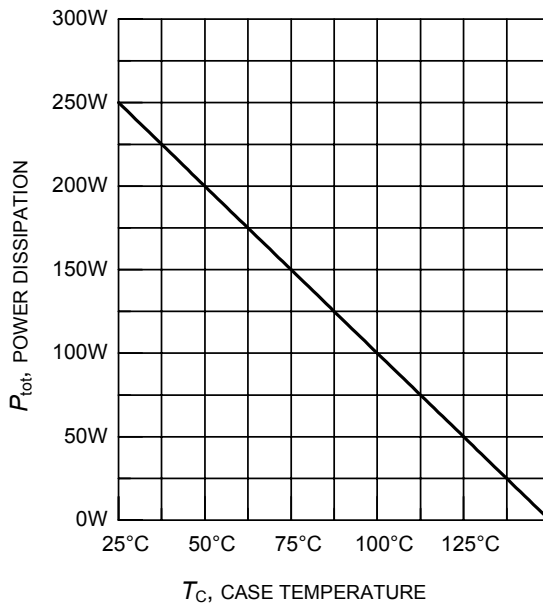
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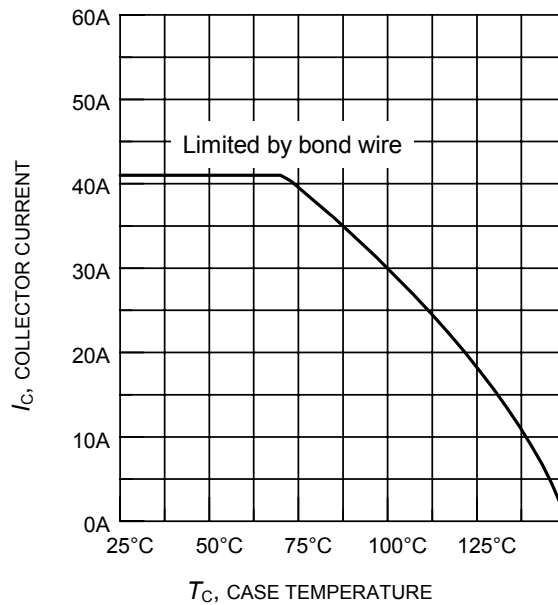
**Figure 1. Collector current as a function of switching frequency**  
 $(T_j \leq 150^\circ\text{C}, D = 0.5, V_{CE} = 400\text{V}, V_{GE} = 0/+15\text{V}, R_G = 11\Omega)$



**Figure 2. Safe operating area**  
 $(D = 0, T_c = 25^\circ\text{C}, T_j \leq 150^\circ\text{C})$



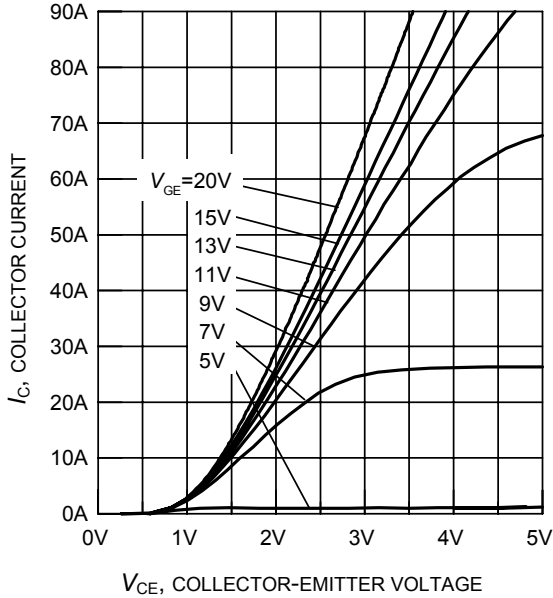
**Figure 3. Power dissipation as a function of case temperature**  
 $(T_j \leq 150^\circ\text{C})$



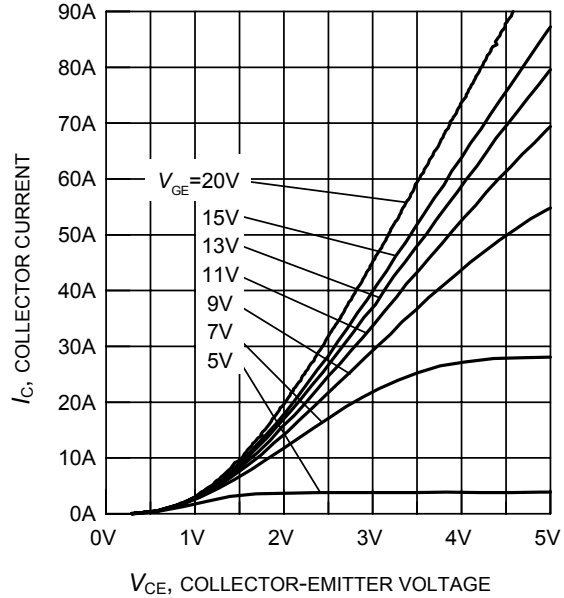
**Figure 4. Collector current as a function of case temperature**  
 $(V_{GE} \leq 15\text{V}, T_j \leq 150^\circ\text{C})$



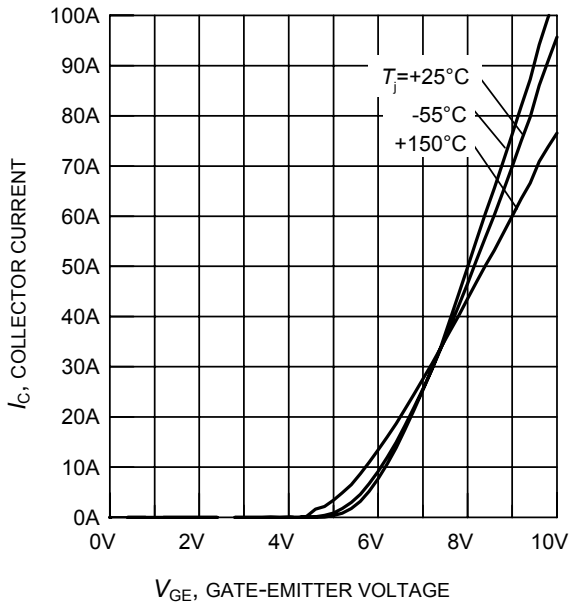
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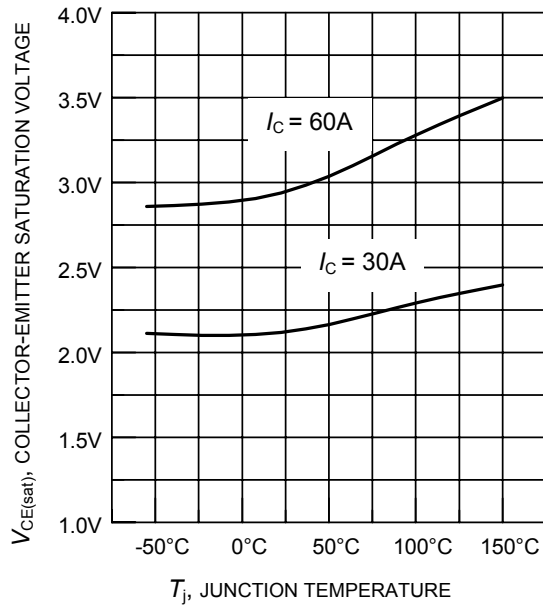
**Figure 5. Typical output characteristics**  
( $T_j = 25^\circ\text{C}$ )



**Figure 6. Typical output characteristics**  
( $T_j = 150^\circ\text{C}$ )



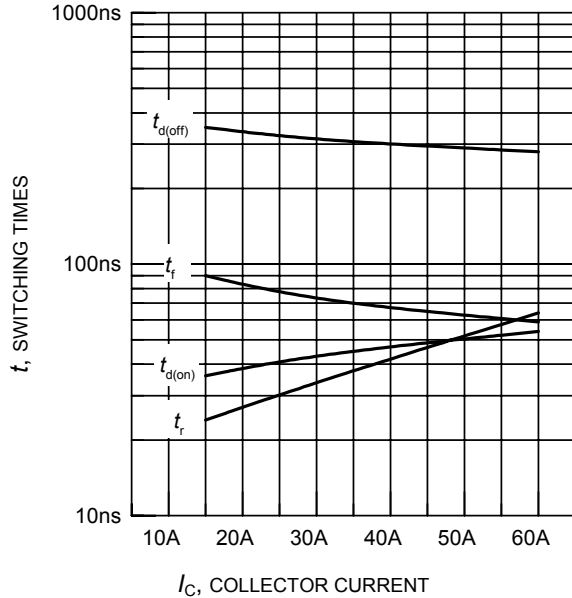
**Figure 7. Typical transfer characteristics**  
( $V_{CE} = 10\text{V}$ )



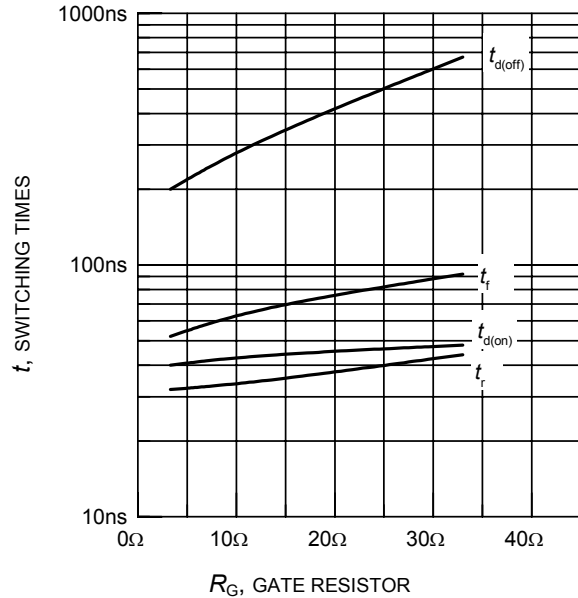
**Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature**  
( $V_{GE} = 15\text{V}$ )



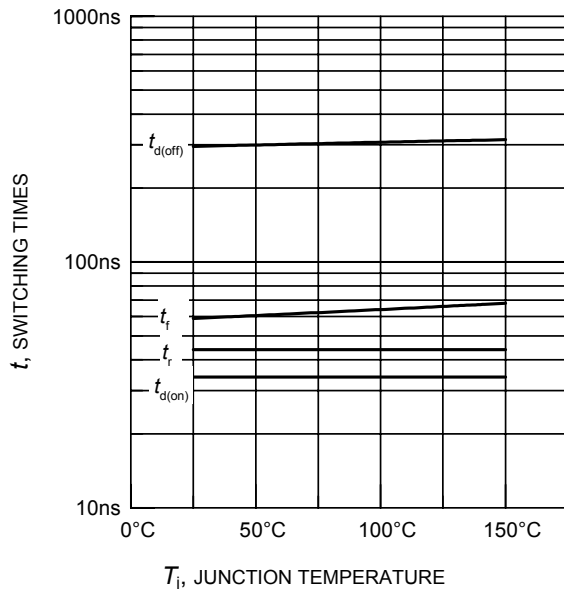
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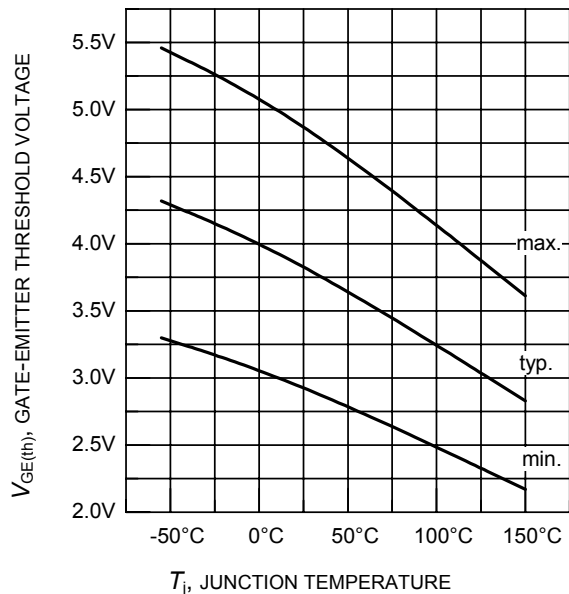
**Figure 9. Typical switching times as a function of collector current**  
 (inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 400\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  $R_G = 11\Omega$ ,  
 Dynamic test circuit in Figure E)



**Figure 10. Typical switching times as a function of gate resistor**  
 (inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 400\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  $I_C = 30\text{A}$ ,  
 Dynamic test circuit in Figure E)



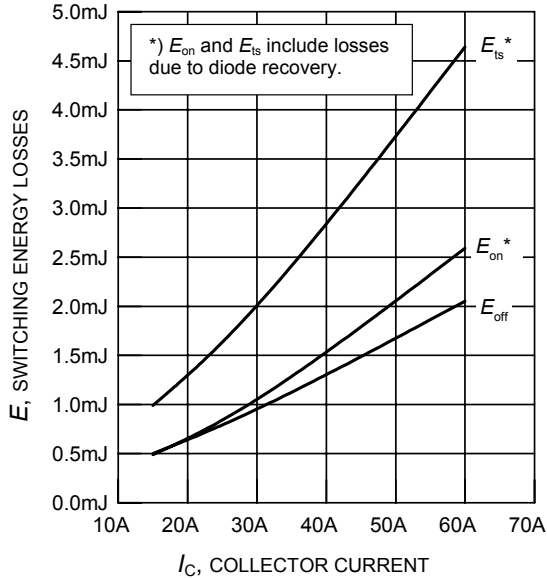
**Figure 11. Typical switching times as a function of junction temperature**  
 (inductive load,  $V_{CE} = 400\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  
 $I_C = 30\text{A}$ ,  $R_G = 11\Omega$ ,  
 Dynamic test circuit in Figure E)



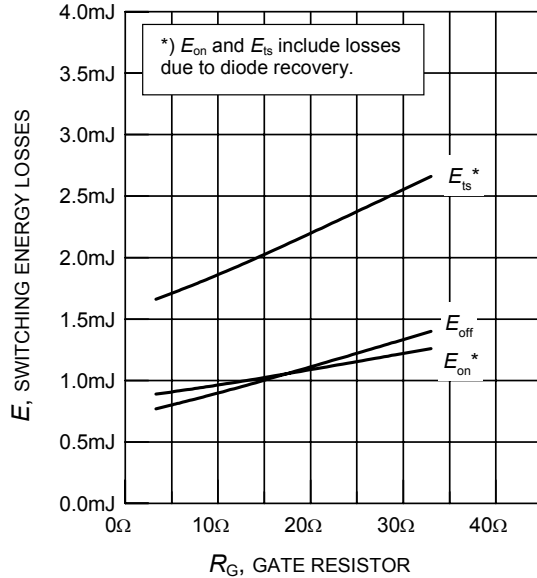
**Figure 12. Gate-emitter threshold voltage as a function of junction temperature**  
 ( $I_C = 0.7\text{mA}$ )



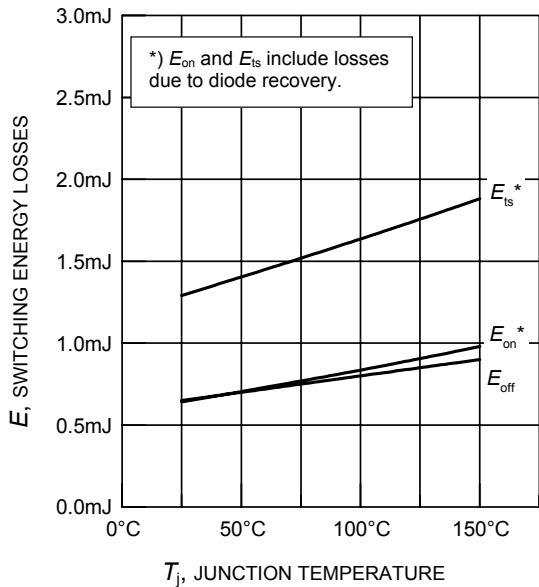
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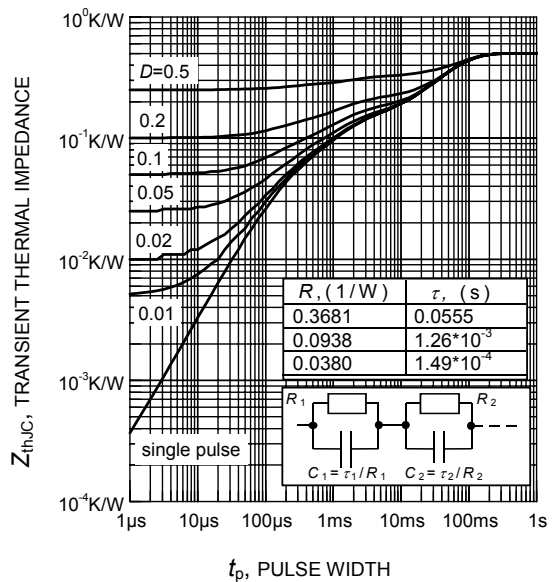
**Figure 13. Typical switching energy losses as a function of collector current**  
 (inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 400\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  $R_G = 11\Omega$ , Dynamic test circuit in Figure E)



**Figure 14. Typical switching energy losses as a function of gate resistor**  
 (inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 400\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  $I_C = 30\text{A}$ , Dynamic test circuit in Figure E)



**Figure 15. Typical switching energy losses as a function of junction temperature**  
 (inductive load,  $V_{CE} = 400\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  $I_C = 30\text{A}$ ,  $R_G = 11\Omega$ , Dynamic test circuit in Figure E)

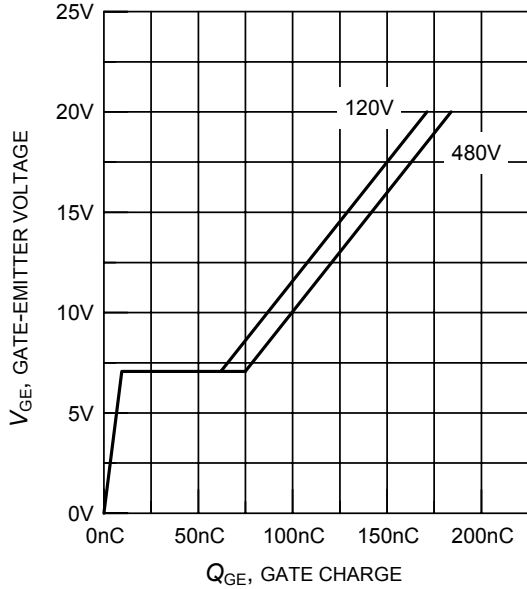


**Figure 16. IGBT transient thermal impedance as a function of pulse width**  
 ( $D = t_p / T$ )

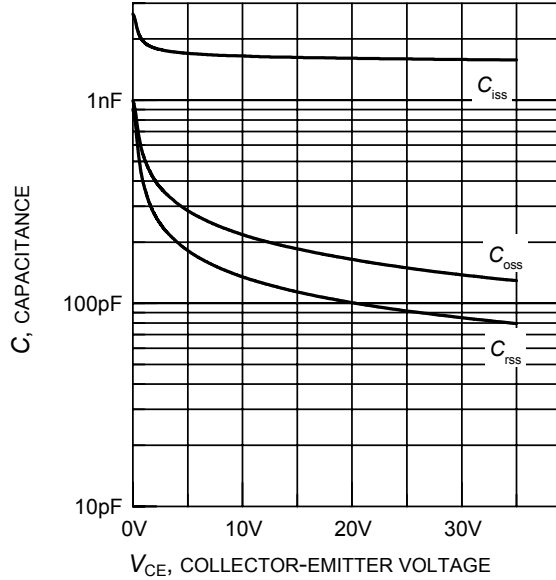




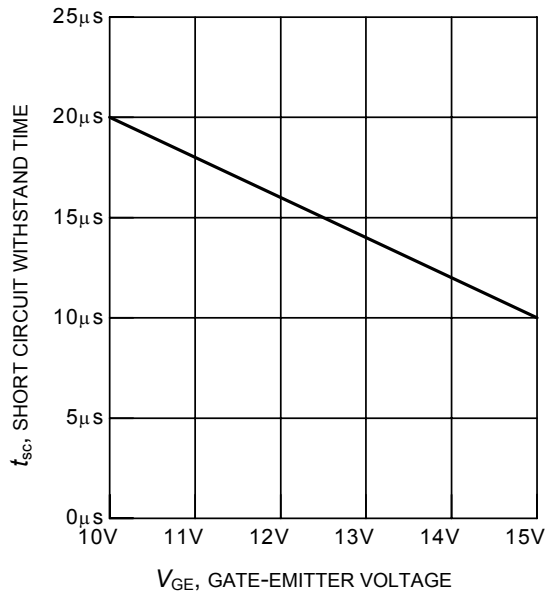
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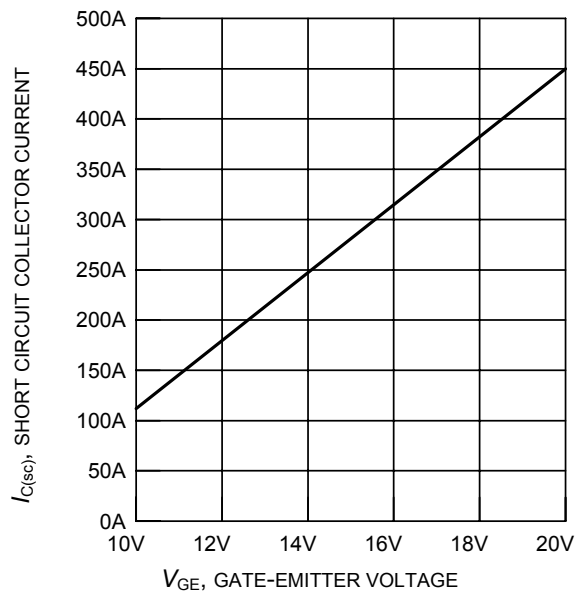
**Figure 17. Typical gate charge**  
( $I_C = 30A$ )



**Figure 18. Typical capacitance as a function of collector-emitter voltage**  
( $V_{GE} = 0V, f = 1MHz$ )



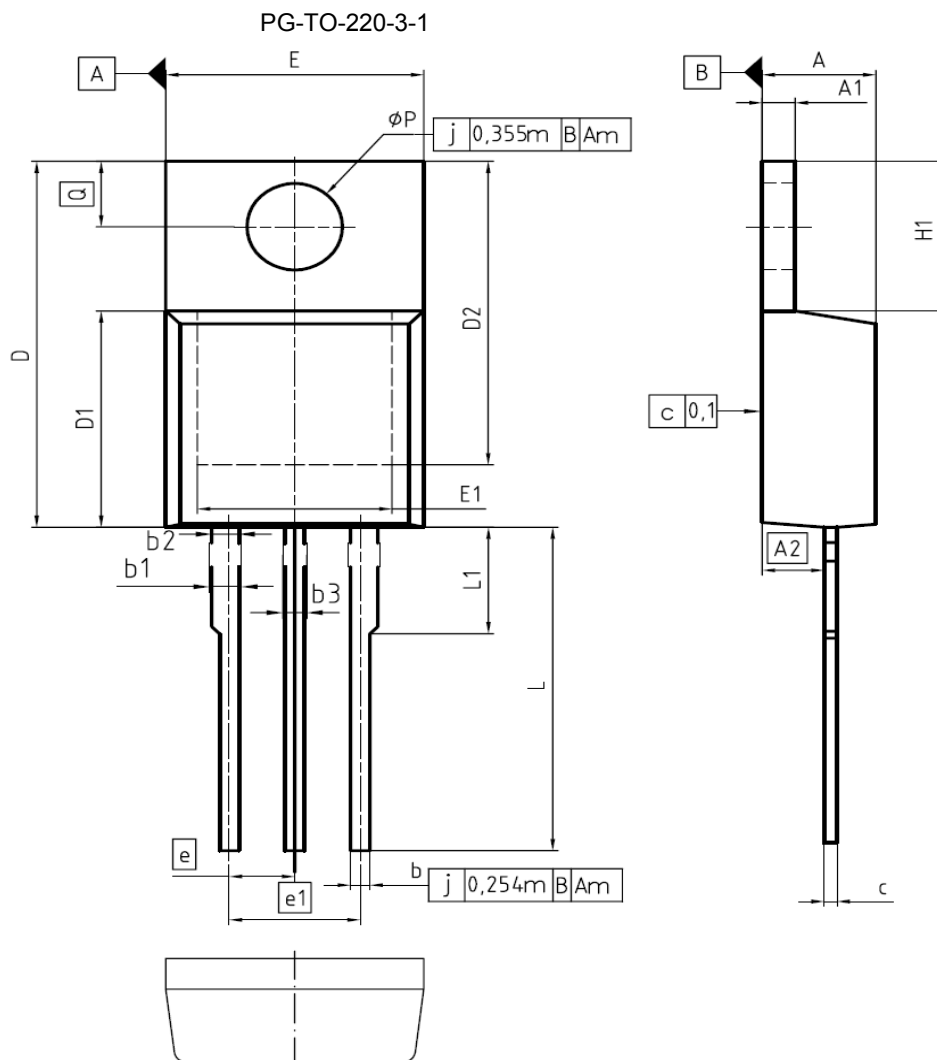
**Figure 19. Short circuit withstand time as a function of gate-emitter voltage**  
( $V_{CE} = 600V, \text{start at } T_j = 25^\circ C$ )



**Figure 20. Typical short circuit collector current as a function of gate-emitter voltage**  
( $V_{CE} \leq 600V, T_j = 150^\circ C$ )



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DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øP	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

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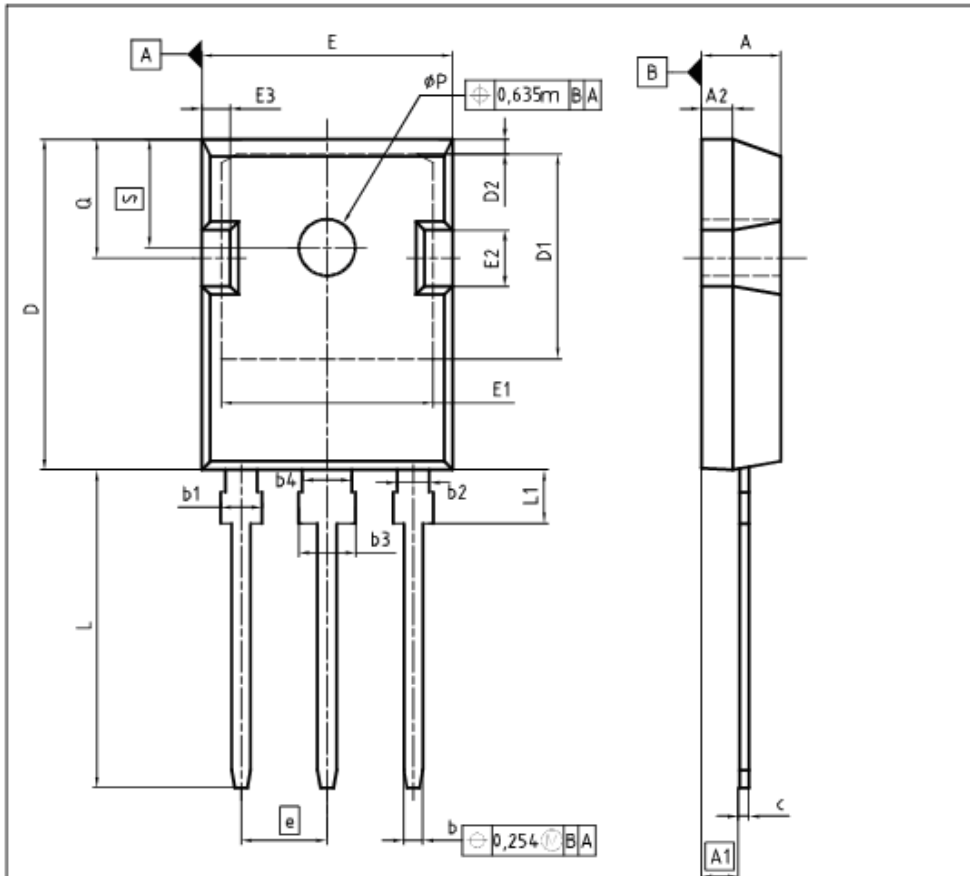
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DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.63	5.21	0.180	0.205
A1	2.27	2.54	0.089	0.100
A2	1.85	2.16	0.073	0.085
b	1.07	1.33	0.042	0.052
b1	1.90	2.41	0.075	0.095
b2	1.90	2.16	0.075	0.085
b3	2.87	3.38	0.113	0.133
b4	2.87	3.13	0.113	0.123
c	0.55	0.68	0.022	0.027
D	20.80	21.10	0.819	0.831
D1	16.25	17.65	0.640	0.695
D2	0.95	1.35	0.037	0.053
E	15.70	16.13	0.618	0.635
E1	13.10	14.15	0.516	0.557
E2	3.68	5.10	0.145	0.201
E3	1.00	2.60	0.039	0.102
e	5.44		0.214	
N	3		3	
L	19.80	20.32	0.780	0.800
L1	4.10	4.47	0.161	0.176
phi P	3.50	3.70	0.138	0.146
Q	5.49	6.00	0.216	0.236
S	6.04	6.30	0.238	0.248

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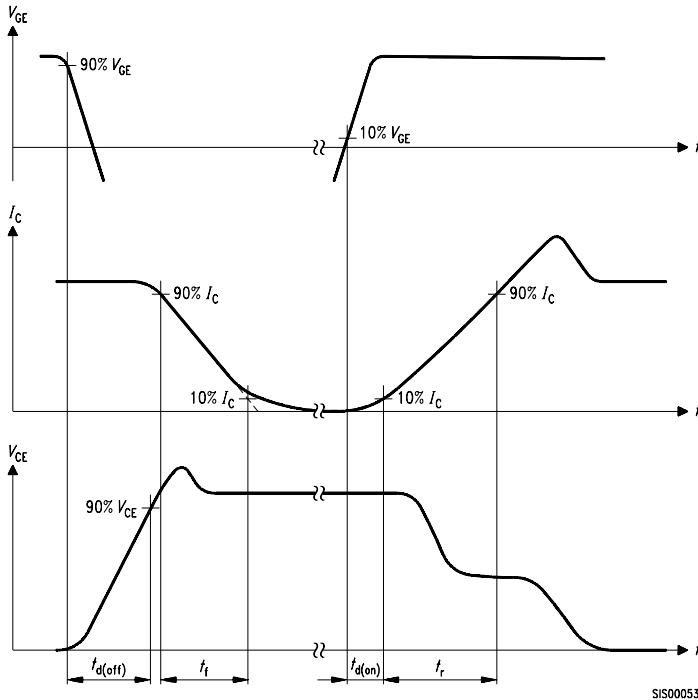
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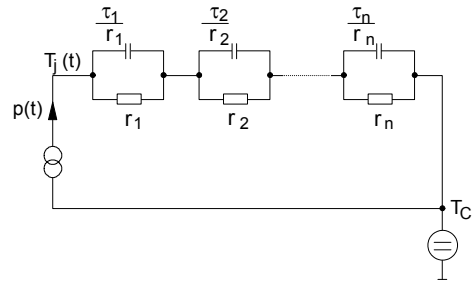
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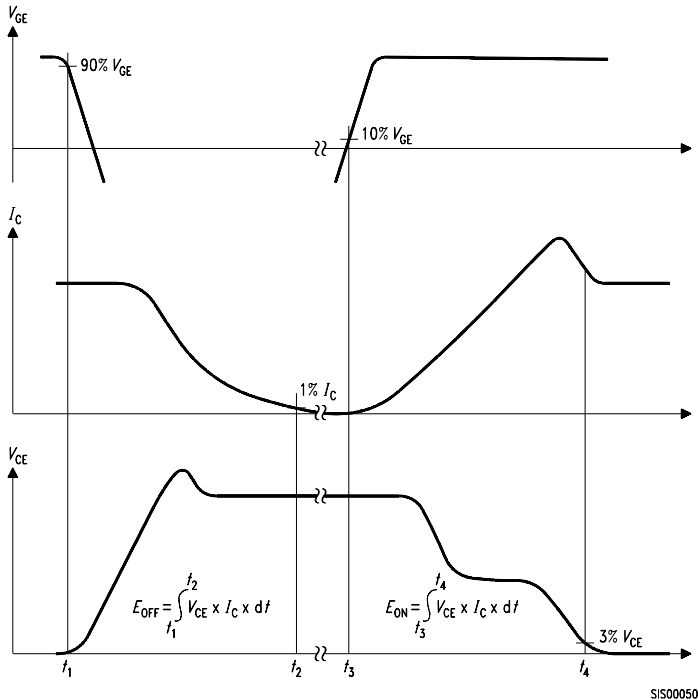
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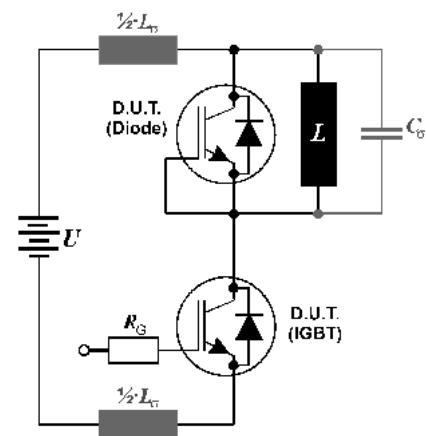
**Figure A. Definition of switching times**



**Figure D. Thermal equivalent circuit**



**Figure B. Definition of switching losses**



**Figure E. Dynamic test circuit**  
 Leakage inductance  $L_{\sigma} = 180\text{nH}$   
 and Stray capacity  $C_{\sigma} = 900\text{pF}$ .



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SGW30N60

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